Analysis of Systematic Effects in 0/45 Lamp-plaque Sensor Calibration

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The 0/45 concept:

- Irradiance-calibrated lamp source (FEL)
- 0/45 BRDF-calibrated diffuse plaque (usu. PTFE)
- Known radiance presented to unit under test (UUT)

Diffusely scattering plaque

Radiometric analysis could include

- Lamp irradiance or intensity vs. distance
- Lamp intensity vs. direction
- BRDF variation when not in 0/45 configuration
- Polarization effects
- Spectral aspects
- Plaque uniformity (position, azimuthal, flatness)

This talk:

- Lamp properties
- BRDF variation
- Comparison of lamp-plaque and integrating-sphere source (ISS) measured by an imager

PTFE Plaque

PTFE Plaque

Geometrical notation at the plaque:

Angle of incidence: θ*i* Direction of incidence: $\mathbf{q}_i = c_{xi} \hat{\mathbf{x}} + c_{yi} \hat{\mathbf{y}} - |c_{zi}| \hat{\mathbf{z}}$

Geometrical notation at the plaque:

Angle of incidence: θ*i* Direction of incidence: $\boldsymbol{q}_i = c_{\chi i} \hat{\boldsymbol{x}} + c_{\chi i} \hat{\boldsymbol{y}} - |\boldsymbol{c}_{z i} | \hat{\boldsymbol{z}}$

Angle of scatter: $\theta_{\rm s}$ Direction of scatter: $\boldsymbol{q}_s = c_{\scriptscriptstyle \chi S} \hat{\boldsymbol{x}} + c_{\scriptscriptstyle \chi S} \hat{\boldsymbol{y}} + |c_{\scriptscriptstyle \chi S} | \hat{\boldsymbol{z}}$

Geometrical notation at the plaque:

Angle of incidence: θ*i* Direction of incidence: $\boldsymbol{q}_i = c_{\chi i} \hat{\boldsymbol{x}} + c_{\chi i} \hat{\boldsymbol{y}} - |\boldsymbol{c}_{z i} | \hat{\boldsymbol{z}}$

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Relative azimuthal angle: ϕ_r

2 0,1,2, 0,1,2 $BRDF(\theta_i, \theta_s, \phi_r)$ $BRDF(0^\circ, 45^\circ, -)$ $g(c_{xi}, c_{yi}; c_{xs}, c_{ys}) = h(l_i, l_s, t_s) = 1 + \sum c_{\mu\nu} l_i^{\mu} l_s^{\nu} + c_t t_s^2$ μ = ν = $= g(c_{xi}, c_{yi}; c_{xs}, c_{vs}) = h(l_i, l_s, t_s) = 1 + \sum c_{\mu\nu}l_i^{\mu}l_s^{\nu} + c_t t_s^2 + ...$ $I_s = sin\theta_s - sin(45^\circ)$ $l_i = sin \theta_i cos \phi_r$ $t_s = \sin \theta_i \sin \phi_r$ **Parametrization of ratio:** Expansion about 0/45 configuration… (1.) Introduce 3 small parameters (2.) Use a low-order polynomial:

Spectral tri-function automated reference Reflectometer (STARR) *Catherine C. Cooksey*

- In-plane BRDF (φ*^r* =0° or 180°)
- Variable θ*ⁱ* , θ*^r*
- Directional/hemispherical
- 250 nm to 2500 nm

Goniometric optical scatter instrument (GOSI) *Thomas A. Germer, Heather Patrick*

- Full BRDF, laser-based (Si region)
- Includes out-of-plane

Future: ROSI (Robotic Optical Scatter Instrument), which is slated to take on STARR capabilities for customers, with full BRDF *Heather Patrick*

Parametrization of ratio

$$
\frac{\text{BRDF}(\theta_i, \theta_s, \phi_r)}{\text{BRDF}(0^\circ, 45^\circ, -)} = g(c_{xi}, c_{yi}; c_{xs}, c_{ys}) = 1 + \sum_{\mu=0,1,2,} c_{\mu\nu}l_i^{\mu}l_s^{\nu} + c_t t_s^2 + \dots
$$

Lamp cal: FASCAL-2 (50 cm, on axis) Distance effect: "uniformity test" [Yoon et al., Proc. SPIE 8510, 85100D (2012)]

$$
E(x, y, z; \lambda) = E_{\text{cal}}(\lambda) \left(\frac{d_{\text{eff}}}{d_{\text{cal}} + 0.2175 \text{ cm}} \right)^2 \left(\frac{I(x, y, z)}{I(0, 0, z)} \right)_{\text{GSF}} \cos \theta_i
$$

Validation of 1/*r*² law presented by Yoon *et al.*

Angular effects on intensity: Gonio Spectroradiometer Facility (GSF, Yuqin Zong)

361 directions:

- -9 deg lat. To +9 deg lat.
- -9 deg long. to +9 deg long.

Relative

Polarization aspects:

- 2.5 % polarized, tipped about 10° (like coils of large helix towards the viewer.)
- Ellipse exaggerates anisotropy.
- Plaque reduces polarization
- Total flux barely affected.

K.J. Voss and L.B. da Costa, Appl. Opt. **55** (31) 8829 (2016).

Note: spectral effects are weak.

Conceptual framework for demonstration experiment--UNIT UNDER TEST (UUT): λ dispersion **Pupil, maps** Angle dispersion **Angle dispersion angles on slit (focus=**∞**)** Angle dispersion **Angle dispersion** *ω* ˆ **Radiant surface Pixel FPA (2D) Slit (1D)** $\frac{P}{P}N = \hat{\omega}$ **or scene Footprint of pupil (in cylinder along given direction) Offner-type spectrometer**

Power delivered to pixel for integrating-sphere source (ISS) & lamp/plaque cases:

 $U_{\lambda} = d\omega | A_{\text{UUT}} \cos \theta_{\text{pixel}} \sec \theta_{\text{s}} | [L_{\text{ISS}} \cos \theta_{\text{s}}]$ PUPIL $\Phi_{\lambda} = d\omega \left[A_{\text{UUT}} \cos \theta_{\text{pixel}} \sec \theta_{\text{s}} \right]$ **ISS radiance, cosine factor Cosine factor (projected UUT pupil area) ISS wall or plaque area enclosed In cylinder** $\{E_{\lambda} \cdot g(...) \cdot BRDF(0/45) \cdot \cos \theta_{s}\}$ $\lambda = d\omega$ $A_{\text{UUT}} \ \cos \theta_{\text{pixel}} \sec \theta_{\text{s}}$ PUPIL ω A_{unr} cos θ_{pinal} sec θ . $\langle \times {\mathcal{E}}_{{\lambda}} \cdot g(...) \cdot \mathsf{BRDF}(0/45) \cdot \cos \theta_{\lambda} \rangle$ $\Phi_{\lambda} = d\omega \left[A_{\text{UUT}} \cos \theta_{\text{pixel}} \sec \theta_{\text{s}} \right]$ **Pixel FOV Irradiance in FOV, g-factor, BRDF, cosine factor** *ISS case Lamp/plaque case*

−*ω* ˆ

−*ω* ˆ

θ *s*

 $\hat{\bm{n}}$

n $\hat{\hat{\bm{n}}}$

Note: (1.) UUT & lamp distance to plaque differ; (2.) need to map sphere; (3.) minimum work distance effects may also matt

Various effects on signal in lamp-plaque case:

Conclusions—

Lamp/plaque introduces effects in sensor calibrations that differ from those of integrating spheres

The effects can depend on the lamp

Optics of sensors (e.g., working distance) may need to be known

Further work is needed to finalize quantitative analysis